

### **Automated design error debug using high-level decision diagrams and mutation operators**

**Raik, Jaan; Repinski, Urmas; Tšepurov, Anton; Hantson, Hanno; Ubar, Raimund-Johannes; Jenihhin, Maksim**

Microprocessors and Microsystems 2013 / p. 505-513 : ill <https://doi.org/10.1016/j.micpro.2012.11.004> Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

### **Combining dynamic slicing and mutation operators for ESL correction**

**Repinski, Urmas; Hantson, Hanno; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes** Proceedings : 2012 17th IEEE

European Test Symposium (ETS) : May 28th-June 1st, 2012, Annecy, France 2012 / [6] p. : ill  
<https://ieeexplore.ieee.org/document/6233020>

### **Comparison of model-based error localization algorithms for C designs**

**Repinski, Urmas; Raik, Jaan** Proceedings of IEEE East-West Design & Test Symposium (EWDTS'2012) : Kharkov, Ukraine,

September 14–17, 2012 2012 / p. 42-45 <https://ieeexplore.ieee.org/document/6673203>

### **Design error diagnosis using backtrace algorithm on decision diagrams**

**Repinski, Urmas; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim; Tšepurov, Anton** Info- ja

kommunikatsioonitehnoloogia doktorikooli IKTDK neljanda aastakonverentsi artiklite kogumik : 26.-27. novembril 2010, Essu mõis 2010 / p. 93-96

### **Diagnosis and correction of multiple design errors using critical path tracing and mutation analysis**

**Hantson, Hanno; Repinski, Urmas; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes** LATW 2012 : 13th IEEE Latin-

American Test Workshop proceedings : April 10th-13th, 2012, Quito, Ecuador 2012 / [6 p.] : ill

<https://ieeexplore.ieee.org/document/6261234>

### **FoREnSiC – an automatic debugging environment for C programs**

Bloem, Roderick; **Raik, Jaan; Repinski, Urmas** Eighth Haifa Verification Conference : HVC 2012 : November 6-8, Haifa, Israel :

[proceedings] 2013 / p. 260-265 : ill [https://doi.org/10.1007/978-3-642-39611-3\\_24](https://doi.org/10.1007/978-3-642-39611-3_24) Conference Proceedings at Scopus Article at Scopus

### **High-level decision diagram simulation for diagnosis and soft-error analysis**

**Raik, Jaan; Repinski, Urmas; Jenihhin, Maksim; Chepurov, Anton** Design and test technology for dependable systems-on-chip

2011 / p. 294-309 : ill <https://www.igi-global.com/chapter/high-level-decision-diagram-simulation/51406>

### **High-level design error diagnosis using backtrace on decision diagrams**

**Raik, Jaan; Repinski, Urmas; Ubar, Raimund-Johannes; Jenihhin, Maksim; Tšepurov, Anton** 28th Norchip Conference :

Tampere, Finland, 15-16 November 2010 : conference program and papers 2010 / [4] p. : ill

<http://dx.doi.org/10.1109/NORCHIP.2010.5669486>

### **Model-based verification with error localization and error correction for C designs**

**Repinski, Urmas** Программные продукты и системы = Programmnye produkty i sistemy = Software & systems 2012 / p. 221-229 :

ill

### **Верификация на основе симуляции с нахождением и исправлением ошибок для С-дизайнов**

**Repinski, Urmas** Программные продукты и системы = Programmnye produkty i sistemy = Software & systems 2012 / c. 229-237 :

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